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Supporting Information

Te-Embedded Nanocrystalline PbTe Thick Films: Structure and Thermoelectric Properties Relationship

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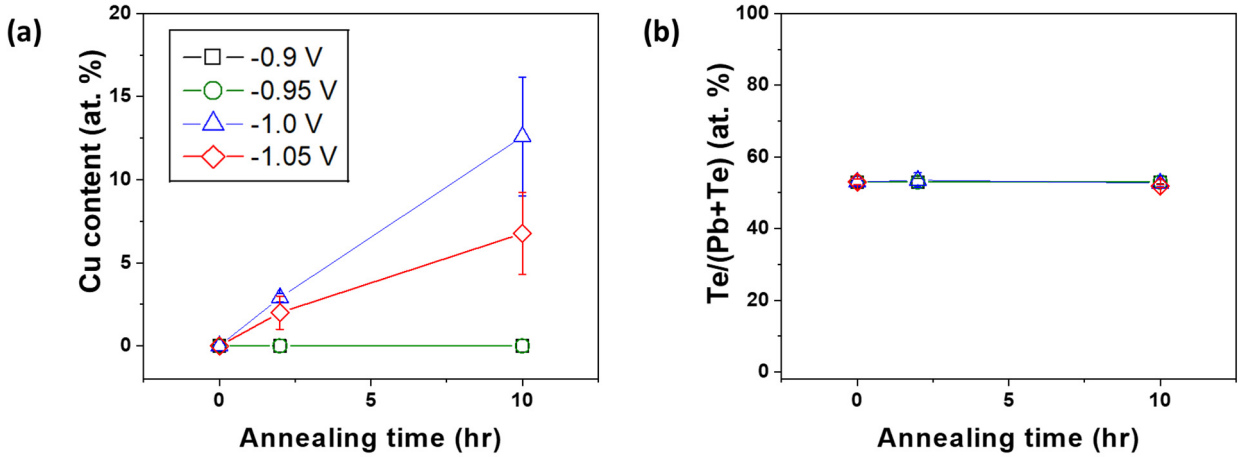

Figure S1. Cu content (a) and ration of Te/(Pb+Te) (b) as a function of annealing temperature for as-deposited and annealed (2 and 10 hours) PbTe film deposited at −0.9, −0.95, −1.0, −1.05 V vs. Ag/AgCl.

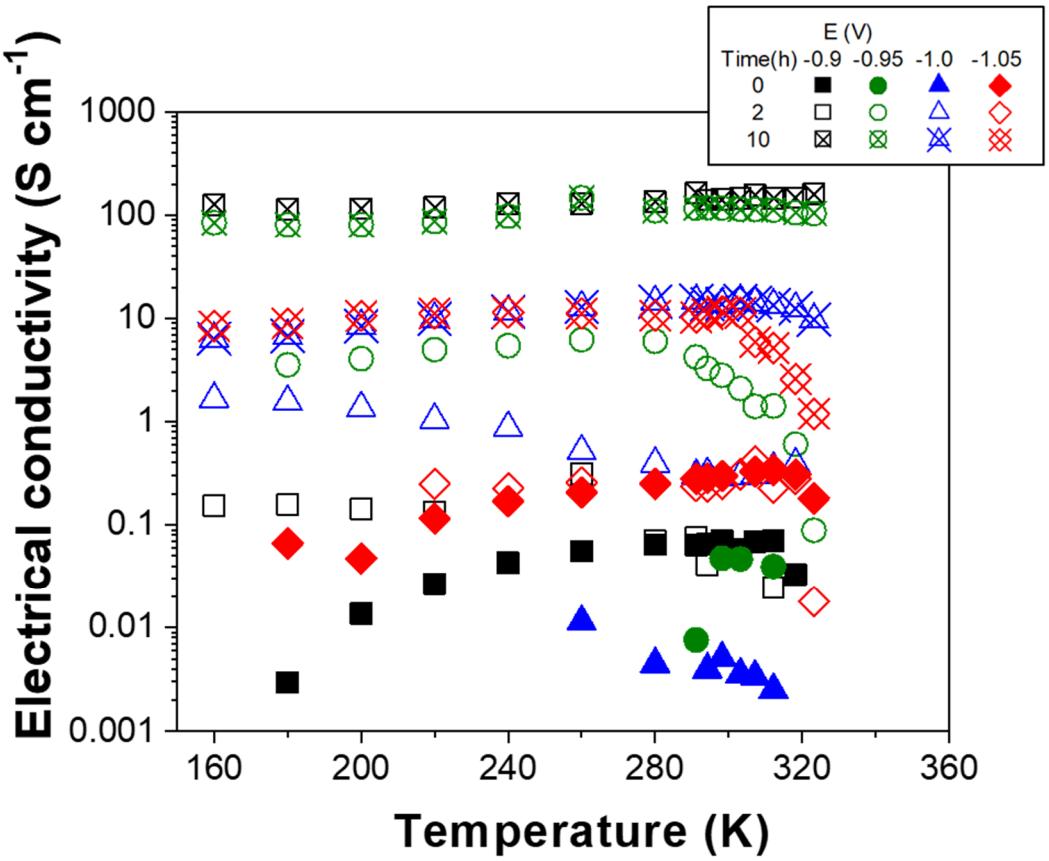

Figure S2. Electrical conductivity as a function of measurement temperature for as-deposited and annealed (2 and 10 hours) PbTe film deposited at −0.9, −0.95, −1.0, −1.05 V vs. Ag/AgCl.

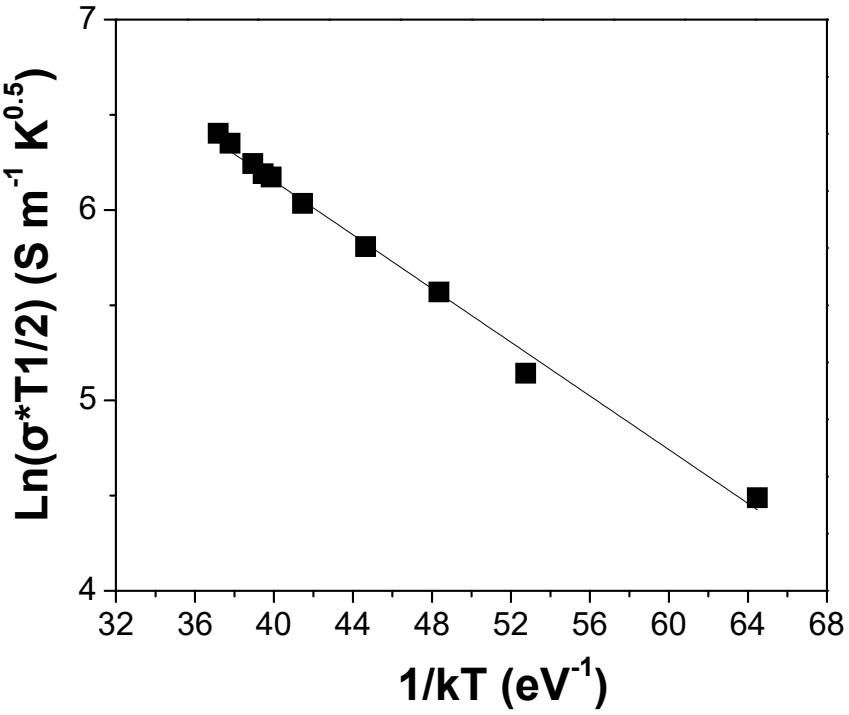

Figure S3. Ln(σ*$T^{1/2}$) as a function of 1/kT used to extract energy barrier height.